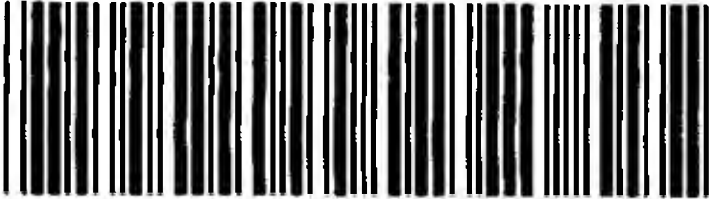


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/584,134	YOSHIDA, NAOHIRO	
	Examiner	Art Unit	
	Hau V. Phan	3618	

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Class	Subclass	Date	Examiner
180	65.3	11/2/2007	HP
	65.4		
	65.2		
	65.8		
	65.6		
429	17	11/2/2007	HP
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318	727	11/2/2007	HP
	700		
320	104	11/2/2007	HP
	126		
	101		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text Search	11/2/2007	HP